

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

Application No.: 10/020 774

Filed: 12-11-01

For: MICROELECTRODE,

MICROELECTRODE ARRAY AND METHOD FOR MANUFACTURING

THE MICROELECTRODE

Art Group: 1745

Examiner: NOG 4625 A

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.97

Assistant Commissioner for Patents Washington, D.C. 20231

Sir:

Pursuant to Rule 1.97, Applicant desires to make of record the reference(s) set forth on the attached Form PTO 1449. A copy of each reference is submitted herewith.

It is hereby stated that this Information Disclosure Statement is being filed within three months of the filing date of the subject application, therefore no petition or fee is required. However, in the event a petition is needed for consideration of this Information Disclosure Statement, Applicant hereby so petitions. Please charge any additional fee due to Deposit Account 02-2666.

Respectfully submitted.

BLAKELY, SOKQLOFF, TAYLOR & ZAFMAN LLP

Date:

Eric S. Hyman, Reg. Soc. 30,139

12400 Wilshire Blvd., 7th Floor Los Angeles, California 90025

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Attorney Docket No.:

Express Mail No.:

EL651822642US

5882P003

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re the Application of:

HAE SIK YANG, ET AL.

Art Group:

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Eric S. Hyman, Reg. No. 30,

12400 Wilshire Blvd., 7th Floor Los Angeles, California 90025

Form PTO-1449 (Modified)	Atty Docket No. 5882P003	Application No.	or Ta
List of Patents & Publications Statement	Applicant(s): Hae Sik Yang, et al.	••	0.8. 0.8.
(Use several sheets if necessary)	Filing Date:	Group No.:	C675

U.S. PATENT DOCUMENTS

Exam. Initials		Document Number	Date	Name	Class	Sub- class	Filing Date (if appropriate)
	AA	6017696	01/25/2000	Heller	435	6	
·	AB	6023091	02/08/2000	Koch et al.	257	536	,
<u>'</u>	AC	5948361	09, 07, 1999	D'Aragona et al.	422	98	•
·	AD	5907765	. (05,125,11999)	Lescouzeres et al.	438	49	•
i i	AE	5296408	03/22/1994	Wilbarg et al.	437	203	
	AF	5849486	: 12/15/1998	Heller et al.	435	6	
	AG	5605662	02, 25/1997	Heller et al.	422	68.1	
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FOREIGN PATENT DOCUMENTS

Exam. Initials	Document Number	Date	Country	Class	Sub- class	Transl Yes	lation No
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OTHER ART (Including Title, Author, Date, Pertinent Pages, etc.)

Exam. Initials		Document Identification
	AR	Electroanalysys 1999, 11, No. 4, pages 223-228
	AS	Journal of Electroanalytical Chemistry 492 (2000), page 150-155
	__\T	TEEE Journal of Microelectromechanical Systems, vol. 8, no. 2, June 1999, pages 135-145

Examiner: Instruct reference considered, whether or not offation is in conformance with MPLP more than a notion against another process for and not considered. Include copy of this torm with next communication.

Form PTO-1449 (Modified)	Atty Docket No. 5882.P003	Application No.
List of Patents & Publications Statement	Applicant(s): Hae Sik Yang, et al.	·
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FOREIGN PATENT DOCUMENTS

Exam. Initials	Document Number	Date	Country	Class	Sub- class	Translation Yes No
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Exam. Initials		Document Identification
	AR	Sensors and Actuators 76 (1999), pages 356-364
	AS	Biosensors & Bioelectronics 14 (1999), pages 443-456

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Examiner: Initial if reference considered whether or not citation is in conformance with MPEP one. Draw the through